



TESTFORUM 2025

Snekkersten, Denmark
December 2nd – 3rd, 2025

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Test Forum 2025 Local Organizer

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Call for Papers / Presentations

The 2-day TestForum 2025, the 23rd event in the series, is the major event for Test professionals in the Nordic area and the Baltic states. Focus is on improving productivity in test of electronics and sharing of new efficient solutions as well as best practices.

Every year, the TestForum is attended by key people from the industry's test community as well as by international vendors of test and measurement equipment and solutions.

In 2025, the event will take place at Comwell Borupgaard, Snekkersten, Denmark.

Nordic Test Forum hereby cordially invites you to participate and submit your contribution to TestForum 2025, which includes (but is not limited to) the following topics:

- *Functional Test*
- *Boundary Scan Test*
- *Embedded Instruments*
- *RF Testing*
- *AOI / AXI / SPI*
- *ICT / Flying Probe*
- *Test economics*
- *Power Test / Battery Test*
- *Test of electronics in automotive, defense and industrial applications*
- *Fixturing / Interfaces*
- *Utilize R&D measurements, fault and test cases for production*
- *Future technology trends and test challenges*
- *Best practices in manufacturing test*
- *Employ semiconductor test solutions at board test.*
- *Board test SW, BIST, diagnostics*
- *Quality methods and tools*
- *Product validation test*
- *Test automation*
- *Robotics in testing*
- *Preventive test / Prognostics*
- *Design to Test transfer / Design for Test*
- *Test efficiency and optimization*
- *Data acquisition / collection / analysis*
- *Safety in testing electronics*

Submissions

TestForum seeks presentations in the area of test of electronics, including *R&D, Application Contributions, Best Practices, Emerging Ideas*, etc. You are welcome to submit contributions also outside the above topics as long as they address the field of electronics test. Focus shall be on new and emerging challenges, opportunities, techniques and best practices in electronics test technology rather than on particular products.

To submit an offer of presentation: Send a title and a 3–6-line abstract on the theme, you offer to present (send to jytte.schneider@nordicestforum.org)

Proceedings

The accepted contributions of presenters that accept hand-out of their presentation will be provided in electronic format (.pdf copies of presentation slides) at the Test Forum event.

The Format of the Event

- The event format: A two-day event/workshop, and an attached small exhibition.
- December 1st in the evening there is the AGM of the NTF.
- The mix of presentations will decide the number of sessions.
- Presentation schedule: 30 minutes each: 25 minutes of speech and 5 minutes for questions and comments.
- In the exhibition, attendees will have an opportunity to see the latest equipment and solutions as well as engaging in dialogues with exhibitors and experts.

Key Dates

- Abstract submission:
- Notification of acceptance:
- Conference registration opens:
- Presentation slides
- **11th August 2025**
- **1st September 2025**
- **18th September 2025**
- **1st November 2025**

Further Information and Submissions

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Visit the NTF web pages at:
<http://www.nordicestforum.org>

NTF
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